

RF Exposure Lab

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CERTIFICATE OF COMPLIANCE RF EXPOSURE & NERVE STIMULATION EVALUATION

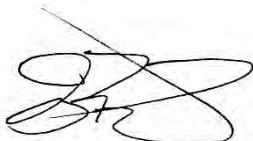
Life Fitness
10601 W. Belmont
Franklin Park, IL 60131

Dates of Test: February 27-28, 2024
Test Report Number: SAR.20240216
Revision B
Lab Designation Number: US1195

| | |
|----------------------|---|
| Contains FCC ID: | LM6-LF10WQWC, LM6-LFNCCR1, WP5-TWN4F3, SQG-60SIPT, XRH-NPE101 |
| Model(s): | Symbio Product Line & Discover SE4 |
| Serial Number: | ILLCONN23120034 |
| Equipment Type: | Wireless Exercise Monitor |
| Classification: | Portable Transmitter Next to Extremity |
| TX Frequency Range: | 125 kHz, 134 kHz (Elatec) & 125 kHz (WPT) |
| Frequency Tolerance: | ± 2.5 ppm |
| Maximum RF Output: | 125 kHz – 17.67 dBm, 134 kHz – 17.67 dBm EIRP |
| Signal Modulation: | ASK |
| Antenna Type: | Internal |
| Application Type: | Certification |
| Standard(s): | KDB680106 v04 |
| Maximum E-Field | 61.53 V/m |
| Maximum H-Field | 1.58 A/m |
| Distance to Probe: | 0 mm |

This wireless mobile device has been shown to meet the requirements for RF exposure testing for uncontrolled environment/general exposure limits specified in above listed standards. The device has also been shown to meet the simultaneous requirements of each standard as well (See test report).

I attest to the accuracy of the data. I assume full responsibility for the completeness of these calculations and vouch for the qualifications of all persons making them.



Jay M. Moulton
Vice President



Testing Certificate # 2387.01

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| Comment/Revision | Date |
|--|-------------|
| Original Release | May 1, 2024 |
| Revision A – Add the ANT+ FCC ID to the product | May 1, 2024 |
| Revision B – Add Discover SE4 as a family member | May 2, 2024 |
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Note: The latest version supersedes all previous versions listed in the above table. The latest version shall be used.

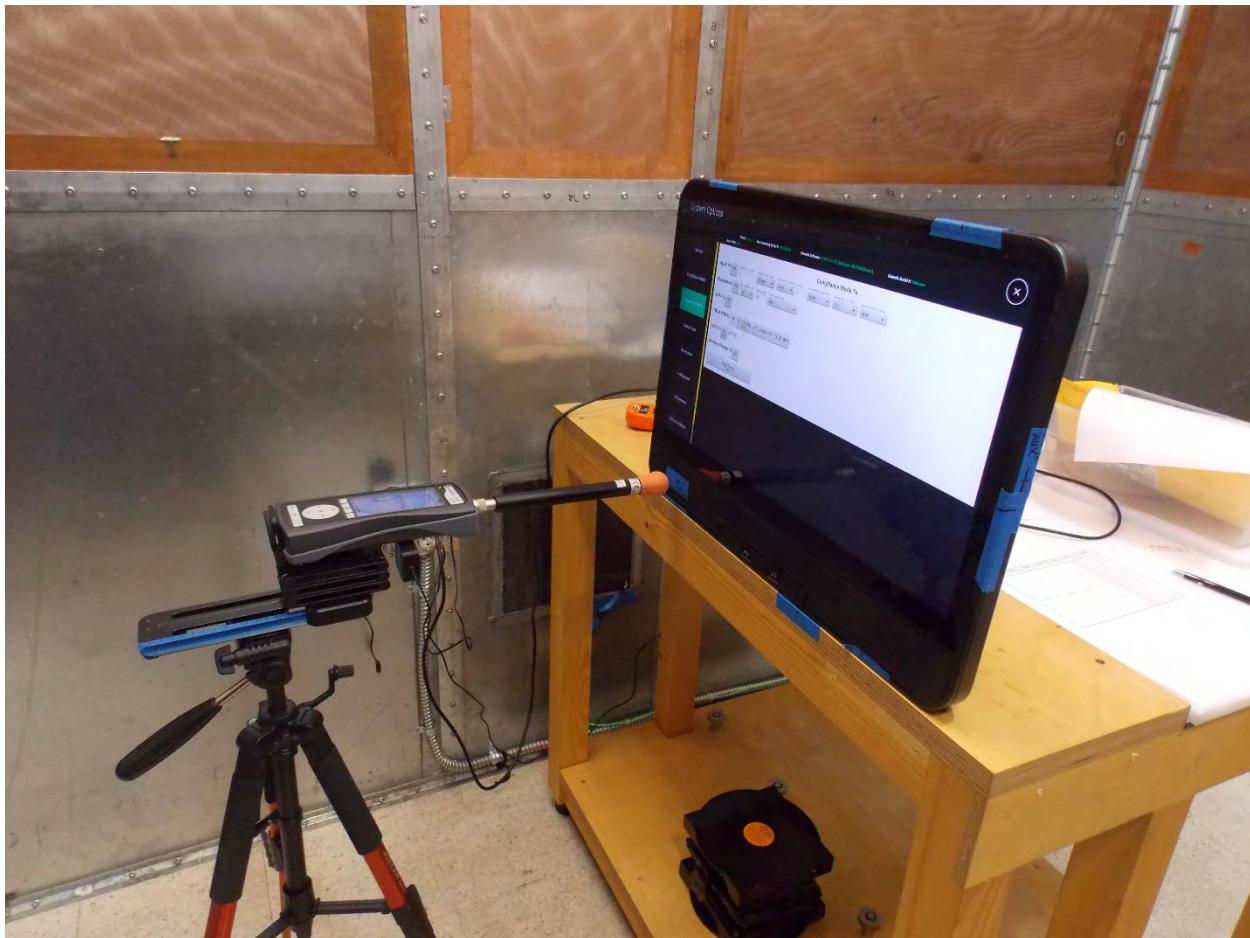
1. Introduction

This report shows RF exposure evaluation of the Life Fitness Model Symbio Product Line & Discover SE4 Wireless Exercise Monitor with KDB680106 v04.

2. Radiation Sources

| Radio | Description | |
|--------------|------------------------|------------------|
| Elatec | Frequency (MHz) | 125 kHz |
| | Maximum Power (dBm) | 17.67 dBm (EIRP) |
| | Maximum Duty Cycle (%) | 100% |
| Elatec | Frequency (MHz) | 134 kHz |
| | Maximum Power (dBm) | 17.67 dBm (EIRP) |
| | Maximum Duty Cycle (%) | 100% |
| Life Fitness | Frequency (MHz) | 125 kHz |
| | Maximum Power (dBm) | 40.00 dBm (EIRP) |
| | Maximum Duty Cycle (%) | 100% |

3. Symbio Product Line



Testing Position for RFID

**Testing Position for Wireless Power Transfer**

4. RF Exposure Classifications

| Device Types | |
|--------------|--|
| Fixed | A fixed device is defined as a device physically secured at one fixed location and cannot be easily re-located. |
| Mobile | A mobile device is defined as a transmitting device designed to be used in other than fixed locations and to generally be used in such a way that a separation distance of at least 20 centimeters is normally maintained between the transmitter's radiating structure(s) and the body of the user or nearby persons. |
| Portable | A portable device is defined as a transmitting device designed to be used so that the radiating structure(s) of the device is/are within 20 centimeters of the body of the user. |

| Exposure Categories | |
|-----------------------------------|--|
| Occupational / Controlled | Limits apply in situations in which persons are exposed as a consequence of their employment provided those persons are fully aware of the potential for exposure and can exercise control over their exposure. Limits for occupational/controlled exposure also apply in situations when an individual is transient through a location where occupational/controlled limits apply provided he or she is made aware of the potential for exposure. |
| General population / uncontrolled | Exposures apply in situations in which the general public may be exposed, or in which persons that are exposed as a consequence of their employment may not be fully aware of the potential for exposure or cannot exercise control over their exposure. |

5. RF Exposure Limits

FCC Requirements

ECFR CONTENT

Table 1 to § 1.1310(e)(1)—Limits for Maximum Permissible Exposure (MPE)

| Frequency range (MHz) | Electric field strength (V/m) | Magnetic field strength (A/m) | Power density (mW/cm ²) | Averaging time (minutes) |
|--|-------------------------------|-------------------------------|-------------------------------------|--------------------------|
| (i) Limits for Occupational/Controlled Exposure | | | | |
| 0.3–3.0 | 614 | 1.63 | *(100) | ≤6 |
| 3.0–30 | 1842/f | 4.89/f | *(900/f ²) | <6 |
| 30–300 | 61.4 | 0.163 | 1.0 | <6 |
| 300–1,500 | | | f/300 | <6 |
| 1,500–100,000 | | | 5 | <6 |
| (ii) Limits for General Population/Uncontrolled Exposure | | | | |
| 0.3–1.34 | 614 | 1.63 | *(100) | <30 |
| 1.34–30 | 824/f | 2.19/f | *(180/f ²) | <30 |
| 30–300 | 27.5 | 0.073 | 0.2 | <30 |
| 300–1,500 | | | f/1500 | <30 |
| 1,500–100,000 | | | 1.0 | <30 |

f = frequency in MHz. * = Plane-wave equivalent power density.

Note: For frequencies below 300 MHz, use the limits at 300 MHz.

6. General Conditions

- This report is only in reference to the item that has undergone the assessment.
- This report does not constitute or imply on its own an approval of the product by the Certification Bodies or Competent Authorities.

7. Environmental Conditions

The following limits were not exceeded during the test:

| | |
|-------------------|--------------|
| Temperature | Min. = 15 °C |
| | Max. = 35 °C |
| Relative Humidity | Min. = 30% |
| | Max. = 60% |

8. Test Equipment

| | Serial Number | Last Cal. Date | Cal. Due Date |
|--|---------------|----------------|---------------|
| • Wavecontrol SMP2 | 19SN1179 | 04/13/2022 | 04/13/2024 |
| • WP400-3 | 19WP120054 | 04/13/2022 | 04/13/2024 |
| • WPH60 | 19WP110048 | 04/13/2022 | 04/13/2024 |
| • WPF6 | 19WP060233 | 04/13/2022 | 04/13/2024 |
| • Positioning Apparatus used is a plastic tripod to hold the meter and probe at a specified position | | | |

9. EUT Description

The description of the antenna is listed below

- There is one antenna in the device for the Elatec 125 kHz and 134 kHz transmitter
- There is one antenna in the Wireless Power Transfer optional device
- The element is a flat concentric wound with an impedance of 490 μ H for the RFID
- The element is a flat concentric wound with an impedance of 1.01 μ H for the WPT
- The shielding or field shaping is not applicable
- The overall dimensions of the PCB for the RFID is 70 mm x 50 mm
- The distance from the antenna to the outside of the enclosure is 6 mm
- The position of the antenna is located in the lower left corner of the monitor
- The enclosure over the antenna is a plastic material

10. RF exposure Evaluation Results

The measurements for the Symbio Product Line was conducted at 20 mm distance from the device to the center of the probe diameter. A pre-scan of the around the antenna was conducted first by moving the probe around all areas of the device being tested. The movement was conducted at a very slow pace to find the peak value for the device. Once the peak position was determined for the device, the meter and probe were installed on the positioning apparatus for conducting the final measurements.

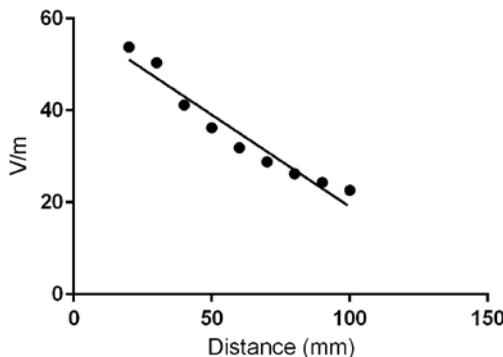
The highest value of the device was then tested every 10 mm moving away from the antenna. All the values were used to extrapolate to the 0 mm distance. The equation used to extrapolate the value to zero is $y = mx + b$, where x is the independent variable, y is the dependent variable, m is the estimated slope and b is the estimated intercept. Below are all the measured values for the e- and h-field.

| 125 kHz (Elatec) | | | |
|------------------|-------------|----------|-------------|
| E-Field | | H-Field | |
| Distance | Meas. Value | Distance | Meas. Value |
| 20 mm | 53.78 V/m | 20 mm | 1.18 A/m |
| 30 mm | 50.37 V/m | 30 mm | 0.97 A/m |
| 40 mm | 41.19 V/m | 40 mm | 0.88 A/m |
| 50 mm | 36.23 V/m | 50 mm | 0.91 A/m |
| 60 mm | 31.89 V/m | 60 mm | 0.77 A/m |
| 70 mm | 28.83 V/m | 70 mm | 0.70 A/m |
| 80 mm | 26.24 V/m | 80 mm | 0.65 A/m |
| 90 mm | 24.31 V/m | 90 mm | 0.59 A/m |
| 100 mm | 22.63 V/m | 100 mm | 0.53 A/m |

The slope for the E-Field calculates to be -0.4001 ± 0.03775 .

The Y-intercept for the E-Field calculates to be 59.06 ± 2.466 .

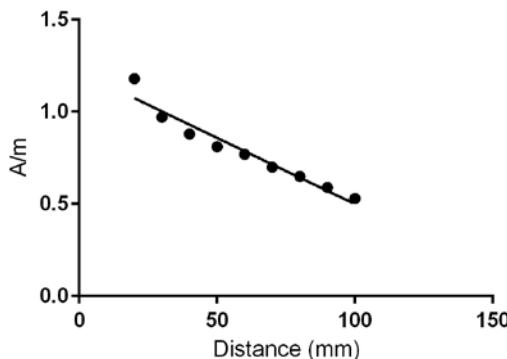
Below is the scatter plot for all the measurements.



The slope for the H-Field calculates to be -0.007183 ± 0.0006726 .

The Y-intercept for the H-Field calculates to be 1.218 ± 0.04393 .

Below is the scatter plot for all the measurements.



The following table shows the maximum value of the device in both the H-Field and E-Field requirement with the limit. The value is the extrapolated value at 0 mm listed in the tables including the tolerance.

| Frequency | E-Field Measurement | Limit [V/m] | % Limit | Verdict |
|-----------|---------------------|-------------|---------|---------|
| 125 kHz | 61.53 | 614 | 10.0 | Pass |

| Frequency | H-Field Measurement | Limit [A/m] | % Limit | Verdict |
|-----------|---------------------|-------------|---------|---------|
| 125 kHz | 1.26 | 1.63 | 77.3 | Pass |

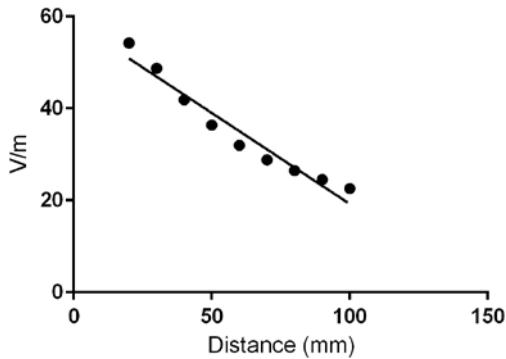
134 kHz (Elatec)

| E-Field | | H-Field | |
|----------|-------------|----------|-------------|
| Distance | Meas. Value | Distance | Meas. Value |
| 20 mm | 54.20 V/m | 20 mm | 0.68 A/m |
| 30 mm | 48.72 V/m | 30 mm | 0.57 A/m |
| 40 mm | 41.87 V/m | 40 mm | 0.51 A/m |
| 50 mm | 36.37 V/m | 50 mm | 0.42 A/m |
| 60 mm | 31.96 V/m | 60 mm | 0.33 A/m |
| 70 mm | 28.81 V/m | 70 mm | 0.25 A/m |
| 80 mm | 26.46 V/m | 80 mm | 0.16 A/m |
| 90 mm | 24.53 V/m | 90 mm | 0.08 A/m |
| 100 mm | 22.59 V/m | 100 mm | 0.06 A/m |

The slope for the E-Field calculates to be -0.3957 ± 0.03478 .

The Y-intercept for the E-Field calculates to be 58.80 ± 2.272 .

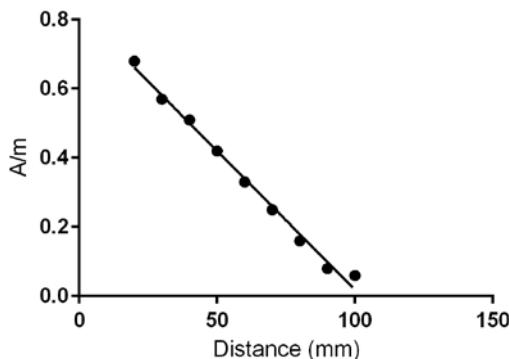
Below is the scatter plot for all the measurements.



The slope for the H-Field calculates to be -0.008033 ± 0.0002757 .

The Y-intercept for the H-Field calculates to be 0.822 ± 0.01801 .

Below is the scatter plot for all the measurements.



The following table shows the maximum value of the device in both the H-Field and E-Field requirement with the limit. The value is the extrapolated value at 0 mm listed in the tables including the tolerance.

| Frequency | E-Field Measurement | Limit [V/m] | % Limit | Verdict |
|-----------|---------------------|-------------|---------|---------|
| 134 kHz | 61.07 | 614 | 9.9 | Pass |

| Frequency | H-Field Measurement | Limit [A/m] | % Limit | Verdict |
|-----------|---------------------|-------------|---------|---------|
| 134 kHz | 0.84 | 1.63 | 51.5 | Pass |

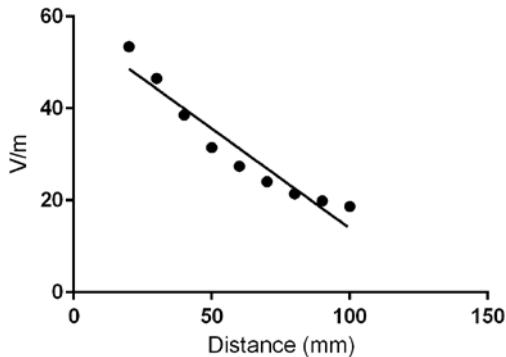
125 kHz (WPT)

| E-Field | | H-Field | |
|----------|-------------|----------|-------------|
| Distance | Meas. Value | Distance | Meas. Value |
| 20 mm | 53.41 V/m | 20 mm | 1.18 A/m |
| 30 mm | 46.51 V/m | 30 mm | 0.97 A/m |
| 40 mm | 38.56 V/m | 40 mm | 0.88 A/m |
| 50 mm | 31.47 V/m | 50 mm | 0.91 A/m |
| 60 mm | 27.43 V/m | 60 mm | 0.77 A/m |
| 70 mm | 24.09 V/m | 70 mm | 0.70 A/m |
| 80 mm | 21.44 V/m | 80 mm | 0.65 A/m |
| 90 mm | 19.89 V/m | 90 mm | 0.59 A/m |
| 100 mm | 18.68 V/m | 100 mm | 0.53 A/m |

The slope for the E-Field calculates to be -0.434 ± 0.04791 .

The Y-intercept for the E-Field calculates to be 57.32 ± 3.13 .

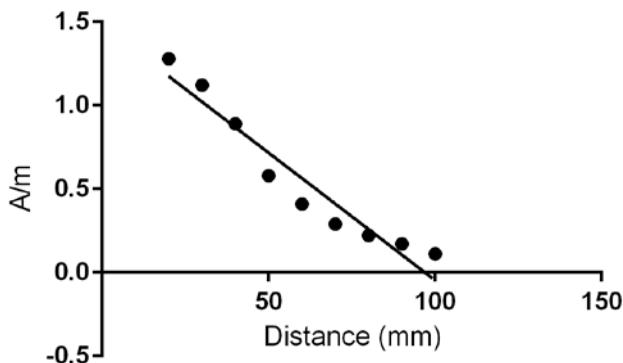
Below is the scatter plot for all the measurements.



The slope for the H-Field calculates to be -0.01527 ± 0.001606 .

The Y-intercept for the H-Field calculates to be 1.479 ± 0.1049 .

Below is the scatter plot for all the measurements.



The following table shows the maximum value of the device in both the H-Field and E-Field requirement with the limit. The value is the extrapolated value at 0 mm listed in the tables including the tolerance.

| Frequency | E-Field Measurement | Limit [V/m] | % Limit | Verdict |
|-----------|---------------------|-------------|---------|---------|
| 125 kHz | 60.45 | 614 | 9.9 | Pass |

| Frequency | H-Field Measurement | Limit [A/m] | % Limit | Verdict |
|-----------|---------------------|-------------|---------|---------|
| 125 kHz | 1.58 | 1.63 | 96.9 | Pass |

Appendix A – Calibration Certificates



Certificate of Calibration

ISO/IEC 17025:2017 and ANSI/NCSL Z540.1-1994

Certificate Number 220411-085519-f52052



Model Number WP400-3; SMP2
Manufacturer Wavecontrol
Description Field Probe
Serial Number 19WP120054; 19SN1179
Customer Asset No. N/A

Customer
RF Exposure Lab, LLC
802 N. Twin Oaks Valley Rd
Suite 105
San Marcos, CA 92069
USA

Date of Calibration 04/13/2022
Temperature 23°C
Humidity 48% RH

Location of Calibration
Keysight Technologies Inc.
1346 Yellowwood Road
Kimballton, IA 51543
United States

This certifies that the equipment has been calibrated using applicable Keysight Technologies procedures and in compliance with ISO/IEC 17025:2017 and ANSI/NCSL Z540.1-1994 (R2002). The quality management system is registered to ISO 9001:2015.

Calibration Standard(s)
IEEE Std 1309-2013

Calibration Method(s)
Substitution

Calibration Procedure(s)
909579

Calibration Software
Probe Comparison 1.4.1

As Received Conditions

The measured values of the equipment were observed in specification at the points tested.

Action Taken

No action was taken.

As Completed Conditions

The measured values of the equipment were observed in specification at the points tested.

Calibration Due

Based on the customer's request, the next calibration is due on 13 Apr 2024

Remarks or Special Requirements

This calibration report shall not be reproduced, except in full. The documented results relate to the equipment calibrated only.

The test limits stated in the report correspond to the published specifications of the equipment, at the points tested.

Keysight Technologies, Inc.
1346 Yellowwood Road
Kimballton, IA 51543
United States

Issue Date 14 Apr 2022


Brandt Langer Iowa Service Center Manager

Page 1 of 4



Certificate of Calibration

ISO/IEC 17025:2017 and ANSI/NCSL Z540.1-1994

Certificate Number 220411-085519-f52052



Traceability Information

Technician Name Dave Grabill

Measurements are traceable to the International System of Units (SI) via national metrology institutes (www.keysight.com/find/NMI) that are signatories to the CIPM Mutual Recognition Arrangement.

Calibration Equipment Used

| Manufacturer | Model Number | Model Description | Equipment ID | Cal Due Date | Certificate Number |
|-----------------------------|----------------|---------------------------------------|--------------|--------------|----------------------|
| Agilent Technologies, Inc. | 33250A | Function/Arbitrary Waveform Generator | 11101 | 06/03/2022 | 210602-130008-794ded |
| AR | 350AH1 | Amp | 11453 | NA | NA |
| Crown | 5002VZ | Amp | 11069 | NA | NA |
| EMCO | 5101 | TEM Cell | 10420 | NA | 2003121920 |
| Hewlett-Packard | 8564E | Spectrum Analyzer | 10029 | 06/02/2022 | 210527-143459-612042 |
| Combinova | FD1 | Field Detector | 10348 | 01/31/2023 | 220104-091355-ad0560 |
| Combinova | FD2 | Field Detector | 10347 | 02/28/2023 | 220201-110452-66d607 |
| Schwarzbeck Mess-Elektronik | FESP 5133-7/41 | Loop | 11285 | 10/31/2022 | 211018-135220-351697 |
| Schwarzbeck Mess-Elektronik | HHS 5204-12 | Helmholtz Coil | 11091 | NA | NA |
| Holaday | HI-3624 | ELF Magnetic Field Meter | 10569 | 09/30/2022 | 210901-094617-c4f116 |
| Holaday | HI-3627 | ELF Magnetic Field Meter | 10570 | 03/31/2023 | 220309-140426-5aaae9 |

Compliance with Specification

Unless otherwise noted, the calibration results are reported without factoring in the effect of uncertainty on the assessment of compliance/specification.

In Specification/Out of Specification Explanation

The standard criteria to determine the "In Specification/Out of Specification" status is based on one or more of the following conditions, as requested by the client:

1. If the manufacturer has a specified specification for the item being calibrated, then the calibration values are compared to this specification, and the values must fall within the manufacturer's specification. The specification may be obtained from the manufacturer's web site, data sheets, equipment manuals, etc.
2. Where specifications are called out in a published standard, the calibration results are compared to this specification, and the measured values must fall within the standard's specification.
3. In cases where the manufacturer, standard, or client does not identify any relevant specifications, applicable calibration results are compared to historical data with a +/- 3 dB specification.

Uncertainty of Measurement

The uncertainty evaluation has been performed in accordance with ISO/IEC Guide 98-3:2008(GUM). The reported expanded uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k such that the coverage probability corresponds to approximately 95%. This probability corresponds to a coverage factor of $k=2$ for a normal distribution.

| Parameter | Range | MU (+/-) |
|-------------------------------------|-----------------|----------------|
| Magnetic Field Strength Meters - AC | 0.20 mG to 20 G | 0.33% + 1.2 mG |

Customer Name: RF Exposure Lab, LLC

Probe Manufacturer: Wavecontrol

Probe Model: WP400-3; SMP2

Probe Serial No.: 19WP120054; 19SN1179

Notes:

CAL CERT #: 220411-085519-f52052

Electric Field

Linearity - 50Hz

| E Field (V/m) | X axis CF | X axis dB | Y axis CF | Y axis dB | Z axis CF | Z axis dB | Mean |
|------------------|--------------|--------------|--------------|--------------|--------------|--------------|------|
| 800 | 1.05 | 0.41 | 1.04 | 0.34 | 1.04 | 0.35 | 1.04 |
| 750 | 1.04 | 0.32 | 1.04 | 0.33 | 1.03 | 0.27 | 1.04 |
| 500 | 1.04 | 0.30 | 1.03 | 0.22 | 1.02 | 0.18 | 1.03 |
| 250 | 1.04 | 0.32 | 1.04 | 0.35 | 1.04 | 0.32 | 1.04 |
| 100 | 1.01 | 0.09 | 1.03 | 0.29 | 0.99 | -0.05 | 1.01 |
| 50 | 1.03 | 0.22 | 1.03 | 0.30 | 1.03 | 0.23 | 1.03 |
| 20 | 1.01 | 0.05 | 1.04 | 0.32 | 1.04 | 0.31 | 1.03 |

Frequency Response

25Hz-100kHz: 750V/m / 10Hz, 200-400kHz: 300V/m

| Freq Hz | X axis CF | X axis dB | Y axis CF | Y axis dB | Z axis CF | Z axis dB | Mean |
|------------|--------------|--------------|--------------|--------------|--------------|--------------|------|
| 10 | 1.31 | 2.37 | 1.30 | 2.31 | 1.31 | 2.37 | 1.31 |
| 25 | 1.14 | 1.16 | 1.16 | 1.26 | 1.15 | 1.23 | 1.15 |
| 50 | 1.06 | 0.54 | 1.07 | 0.56 | 1.07 | 0.61 | 1.07 |
| 100 | 1.09 | 0.77 | 1.09 | 0.77 | 1.10 | 0.83 | 1.10 |
| 500 | 1.10 | 0.82 | 1.09 | 0.72 | 1.10 | 0.81 | 1.09 |
| 1000 | 1.10 | 0.82 | 1.09 | 0.71 | 1.10 | 0.83 | 1.10 |
| 2000 | 1.18 | 1.44 | 1.17 | 1.33 | 1.17 | 1.39 | 1.17 |
| 10000 | 1.07 | 0.57 | 1.05 | 0.45 | 1.07 | 0.57 | 1.06 |
| 100000 | 1.07 | 0.56 | 1.06 | 0.50 | 1.06 | 0.48 | 1.06 |
| 200000 | 1.00 | 0.04 | 1.00 | 0.03 | 1.00 | 0.02 | 1.00 |
| 300000 | 1.05 | 0.44 | 1.05 | 0.46 | 1.05 | 0.43 | 1.05 |
| 400000 | 1.06 | 0.51 | 1.03 | 0.27 | 1.06 | 0.48 | 1.05 |

Customer Name: RF Exposure Lab, LLC

Probe Manufacturer: Wavecontrol

Probe Model: WP400-3; SMP2

Probe Serial No.: 19WP120054; 19SN1179

Notes:

CAL CERT #: 220411-085519-f52052

Magnetic Field

| Linearity - 50Hz | | | | | | | |
|------------------|--------------|--------------|--------------|--------------|--------------|--------------|------|
| B Field (uT) | X axis CF | X axis dB | Y axis CF | Y axis dB | Z axis CF | Z axis dB | Mean |
| 2000 | 1.00 | 0.02 | 1.00 | 0.00 | 1.00 | 0.00 | 1.00 |
| 1500 | 0.97 | -0.26 | 0.96 | -0.33 | 0.96 | -0.36 | 0.96 |
| 1000 | 0.97 | -0.26 | 0.97 | -0.23 | 0.97 | -0.28 | 0.97 |
| 750 | 0.96 | -0.37 | 0.96 | -0.35 | 0.95 | -0.40 | 0.96 |
| 500 | 0.96 | -0.35 | 0.96 | -0.32 | 0.96 | -0.37 | 0.96 |
| 250 | 0.97 | -0.30 | 0.97 | -0.24 | 0.97 | -0.29 | 0.97 |
| 100 | 0.95 | -0.41 | 0.96 | -0.35 | 0.95 | -0.41 | 0.96 |
| 50 | 0.97 | -0.30 | 0.97 | -0.23 | 0.97 | -0.28 | 0.97 |
| 10 | 0.97 | -0.25 | 0.98 | -0.18 | 0.98 | -0.22 | 0.98 |
| 5 | 0.98 | -0.20 | 0.98 | -0.15 | 0.98 | -0.19 | 0.98 |

| Frequency Response | | | | | | | |
|------------------------------------|--------------|--------------|--------------|--------------|--------------|--------------|------|
| 10Hz-2kHz: 100uT / 10-200kHz: 25uT | | | | | | | |
| Freq Hz | X axis CF | X axis dB | Y axis CF | Y axis dB | Z axis CF | Z axis dB | Mean |
| 10 | 0.93 | -0.67 | 0.93 | -0.65 | 0.93 | -0.63 | 0.93 |
| 30 | 1.02 | 0.15 | 1.02 | 0.17 | 1.02 | 0.19 | 1.02 |
| 50 | 0.95 | -0.46 | 0.95 | -0.44 | 0.95 | -0.43 | 0.95 |
| 100 | 0.98 | -0.17 | 0.98 | -0.15 | 0.98 | -0.14 | 0.98 |
| 500 | 1.01 | 0.08 | 1.01 | 0.12 | 1.02 | 0.13 | 1.01 |
| 1000 | 0.95 | -0.43 | 0.96 | -0.38 | 0.96 | -0.38 | 0.96 |
| 2000 | 0.94 | -0.52 | 0.95 | -0.49 | 0.95 | -0.49 | 0.94 |
| 10000 | 0.88 | -1.09 | 0.88 | -1.14 | 0.88 | -1.12 | 0.88 |
| 100000 | 0.87 | -1.16 | 0.87 | -1.25 | 0.87 | -1.26 | 0.87 |
| 200000 | 0.88 | -1.16 | 0.86 | -1.30 | 0.86 | -1.28 | 0.87 |